EIA/JEDEC STANDARD

Test Method A105-B

Power and Temperature Cycling

EIA/JESD22-A105-B
(Revision of Test Method A105-A)

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ELECTRONIC INDUSTRIES ASSOCIATION
ENGINEERING DEPARTMENT
Withdrawn
INTERNATIONAL ELECTROTECHNICAL COMMISSION

POWER AND TEMPERATURE CYCLING

FOREWORD

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IEC-PAS 62206 was submitted by JEDEC and has been processed by IEC technical committee 47: Semiconductor devices.

The text of this PAS is based on the following document:

IEC-PAS 62206

This PAS was approved for publication by the P-members of the committee concerned as indicated in the following document:

Draft PAS

Report on voting

47/1514/PAS

47/1514/RVD

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Withdrawn
TEST METHOD A105-B
POWER AND TEMPERATURE CYCLING

(From Council Ballot JCB-95-85, formulated under the cognizance of JC-14.1 Committee on Reliability Test Methods for Packaged Devices)

1 Purpose

The power and temperature cycling test is performed to determine the ability of a device to withstand alternate exposures at high and low temperature extremes with operating biases periodically applied and removed. It is intended to simulate worst case conditions encountered in typical applications.

The power and temperature cycling test is considered destructive. It is intended for device qualification.